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(74) Agent: MEYER, Michael; Philips Intellectual Property &

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- (71) Applicant (for DE only): PHILIPS INTELLECTUAL PROPERTY & STANDARDS GMBH [DE/DE]; Steindamm 94, 20099 Hamburg (DE).
- (71) Applicant (for all designated States except DE, US): KONINKLIJKE PHILIPS ELECTRONICS N. V. [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).
- (72) Inventors; and
- (75) Inventors/Applicants (for US only): GLEICH, Bernhard [DE/DE]; c/o Philips Intellectual Property & Standards GmbH, Weisshausstr. 2, 52066 Aachen (DE). WEIZENECKER, Jürgen [DE/DE]; c/o Philips Intellectual Property & Standards GmbH, Weisshausstr. 2, 52066 Aachen (DE).

- Standards GmbH, Weisshausstr. 2, 52066 Aachen (DE).
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(54) Title: ELASTOGRAPHY DEVICE AND METHOD FOR DETERMINING AND IMAGING OF MECHANICAL AND ELASTIC PARAMETERS OF AN EXAMINATION OBJECT

(57) Abstract: The present invention relates to a device for determining mechanical, particularly elastic, parameters of an examination object, comprising a) at least one arrangement for determining the spatial distribution of magnetic particles in at least one examination area of the examination object, comprising a means for generating a magnetic field with a spatial profile of the magnetic field strength such that there is produced in at least one examination area a first part-area having a low magnetic field strength and a second part-area having a higher magnetic field strength, a means for detecting signals which depend on the magnetization in the examination object, particularly in the examination area, that is influenced by a spatial change in the particles, and a means for evaluating the signals so as to obtain information about the, in particular temporally changing, spatial distribution of the magnetic particles in the examination area; and b) at least one means for generating mechanical displacements, in particular oscillations, at least in and/or adjacent to the examination area of the examination object. The invention furthermore relates to a method for determining mechanical and/or physical parameters of an examination object, in particular using a device according to the invention. The invention further relates to magnetic particle compositions that can be used in that method according to the invention.